

# 2SB0774 (2SB774)

## Silicon PNP epitaxial planar type

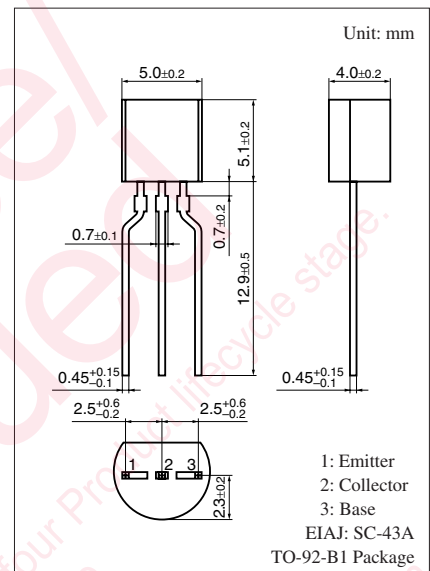
For low-frequency amplification

### ■ Features

- High emitter-base voltage (Collector open)  $V_{EBO}$
- Protective diodes and resistances between emitter and base can be omitted.

### ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	$V_{CBO}$	-30	V
Collector-emitter voltage (Base open)	$V_{CEO}$	-25	V
Emitter-base voltage (Collector open)	$V_{EBO}$	-15	V
Collector current	$I_C$	-100	mA
Peak collector current	$I_{CP}$	-200	mA
Collector power dissipation	$P_C$	400	mW
Junction temperature	$T_j$	150	$^\circ\text{C}$
Storage temperature	$T_{stg}$	-55 to +150	$^\circ\text{C}$



### ■ Electrical Characteristics $T_a = 25^\circ\text{C} \pm 3^\circ\text{C}$

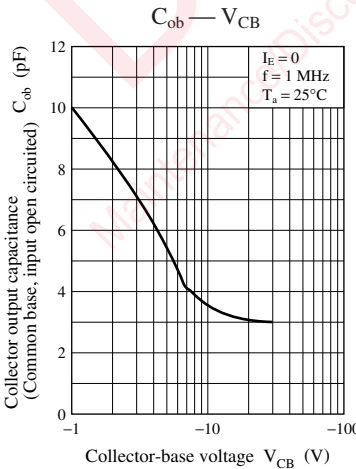
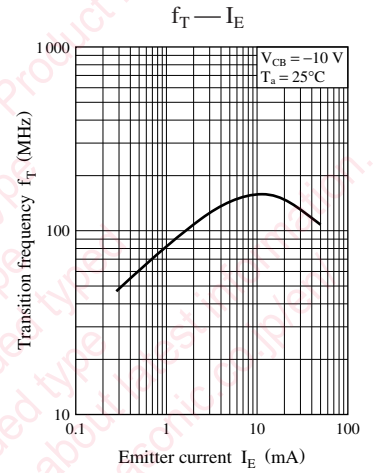
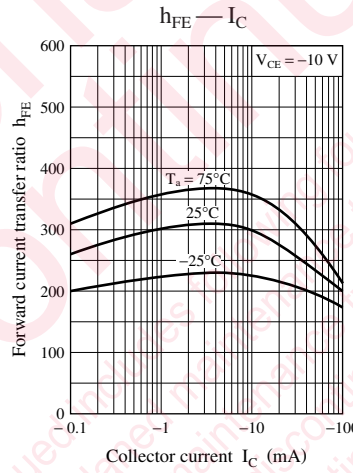
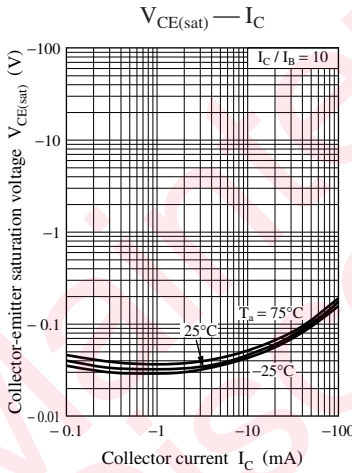
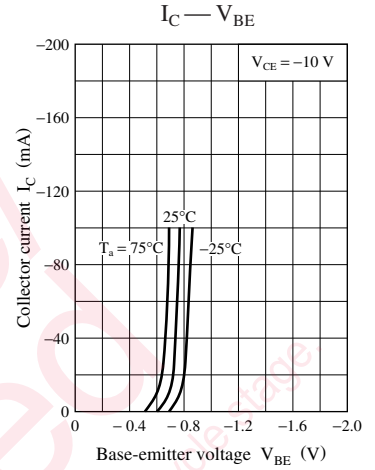
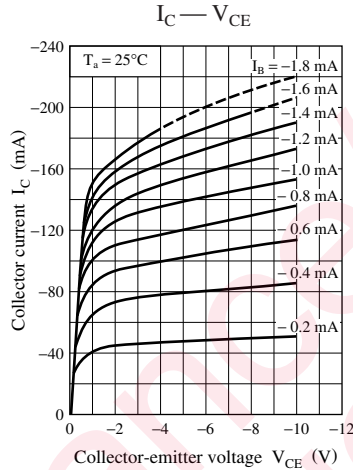
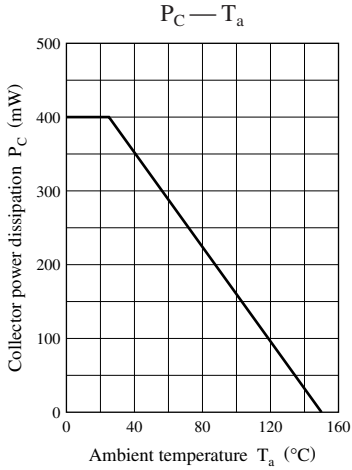
Parameter	Symbol	Conditions	Min	Typ	Max	Unit
Collector-base voltage (Emitter open)	$V_{CBO}$	$I_C = -10 \mu\text{A}$ , $I_E = 0$	-30			V
Collector-emitter voltage (Base open)	$V_{CEO}$	$I_C = -2 \text{ mA}$ , $I_B = 0$	-25			V
Emitter-base voltage (Collector open)	$V_{EBO}$	$I_E = -10 \mu\text{A}$ , $I_C = 0$	-15			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = -10 \text{ V}$ , $I_E = 0$			-1	$\mu\text{A}$
Collector-emitter cutoff current (Base open)	$I_{CEO}$	$V_{CE} = -20 \text{ V}$ , $I_B = 0$			-100	$\mu\text{A}$
Forward current transfer ratio	$h_{FE1}^*$	$V_{CE} = -10 \text{ V}$ , $I_C = -2 \text{ mA}$	210		460	—
	$h_{FE2}$	$V_{CE} = -2 \text{ V}$ , $I_C = -100 \text{ mA}$	90			—
Collector-emitter saturation voltage	$V_{CE(sat)}$	$I_C = -100 \text{ mA}$ , $I_B = -10 \text{ mA}$			-0.5	V
Transition frequency	$f_T$	$V_{CB} = -10 \text{ V}$ , $I_E = 2 \text{ mA}$ , $f = 200 \text{ MHz}$		150		MHz
Collector output capacitance (Common-emitter reverse transfer)	$C_{ob}$	$V_{CB} = -10 \text{ V}$ , $I_E = 0$ , $f = 1 \text{ MHz}$		4		pF

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*: Rank classification

Rank	R	S
$h_{FE1}$	210 to 340	290 to 460

Note) The part number in the parenthesis shows conventional part number.



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